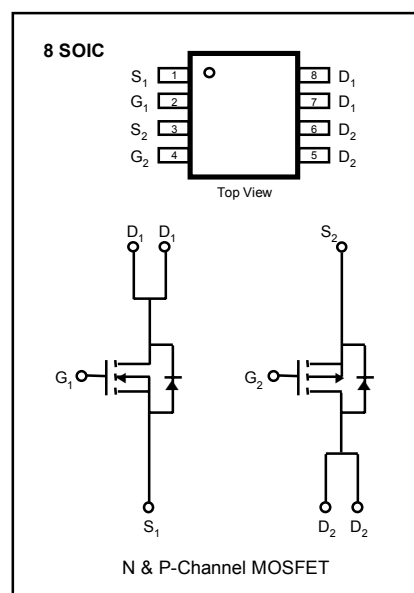


FEATURES

- Lower $R_{DS(ON)}$
- Improved Inductive Ruggedness
- Fast Switching Times
- Low Input Capacitance
- Extended Safe Operating Area
- Improved High Temperature Reliability

Product Summary

SSD2004	BVdss	Rds(on)	I _D
N-Channel	20V	0.125Ω	3.0A
P-Channel	-20V	0.20Ω	-2.5A



Absolute Maximum Ratings

Symbol	Characteristic	N-Channel	P-Channel	Units
V _{DSS}	Drain-to-Source Voltage	20	-20	V
I _D	Continuous Drain Current T _A =25℃	3.0	-2.5	A
	Continuous Drain Current T _A =70℃	2.5	-2.0	
I _{DM}	Drain Current-Pulsed ①	10.0	-10.0	A
V _{GS}	Gate-to-Source Voltage	±20	±20	V
P _D	Total Power Dissipation (T _A =25℃)	2.0		W
	(T _A =70℃)	1.3		
T _J , T _{STG}	Operating and Junction Storage Temperature Range	- 55 to +150		℃

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient	—	62.5	$^\circ\text{C/W}$

(N-Channel)

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	20	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$V_{GS(th)}$	Gate Threshold Voltage	1.0	--	--	V	$V_{DS}=5V, I_D=250\mu A$
I_{GSS}	Gate-Source Leakage , Forward	--	--	100	nA	$V_{GS}=20V$
	Gate-Source Leakage , Reverse	--	--	-100	nA	$V_{GS}=-20V$
I_{DSS}	Drain-to-Source Leakage Current	--	--	2.0	μA	$V_{DS}=16V$
		--	--	25		$V_{DS}=16V, T_C=55^\circ\text{C}$
I_{DON}	On-State Drain-Source Current	10	--	--	A	$V_{DS}=5V, V_{GS}=10V$
$R_{DS(on)}$	Static Drain-Source	--	0.031	0.125	Ω	$V_{GS}=10V, I_D=1.0A$
	On-State Resistance ②	--	0.042	0.25		$V_{GS}=4.5V, I_D=0.5A$
g_{fs}	Forward Transconductance ②	--	8.0	--	S	$V_{DS}=15V, I_D=3.0A$
$t_{d(on)}$	Turn-On Delay Time	--	13	15	ns	$V_{DD}=20V, I_D=1.0A,$ $R_0=6.0\Omega,$ ②③
t_r	Rise Time	--	16	20		
$t_{d(off)}$	Turn-Off Delay Time	--	38	50		
t_f	Fall Time	--	24	50		
Q_g	Total Gate Charge	--	18	25	nC	$V_{DS}=10V, V_{GS}=10V,$ $I_D=2.3A$ ②③
Q_{gs}	Gate-Source Charge	--	2.4	--		
Q_{gd}	Gate-Drain(" Miller ") Charge	--	3.8	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current (Body Diode)	--	--	1.25	A	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier 
V_{SD}	Diode Forward Voltage ②	--	--	1.2	V	$T_A=25^\circ\text{C}, I_S=1.25A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time ②	--	100	--	ns	$T_A=25^\circ\text{C}, I_F=1.25A, di_F/dt=100A/\mu s$

Notes ;

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ② Pulse Test : Pulse Width = $250\mu s$, Duty Cycle $\leq 2\%$
- ③ Essentially Independent of Operating Temperature

(P-Channel)

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	-20	--	--	V	$V_{GS}=0V, I_D=-250\mu A$
$V_{GS(th)}$	Gate Threshold Voltage	-1.0	--	--	V	$V_{DS}=-5V, I_D=-250\mu A$
I_{GSS}	Gate-Source Leakage , Forward	--	--	-100	nA	$V_{GS}=-20V$
	Gate-Source Leakage , Reverse	--	--	100	nA	$V_{GS}=20V$
I_{DSS}	Drain-to-Source Leakage Current	--	--	-2.0	μA	$V_{DS}=-16V$
		--	--	-25		$V_{DS}=-16V, T_C=55^\circ\text{C}$
I_{DON}	On-State Drain-Source Current	-2.3	--	--	A	$V_{DS}=-5V, V_{GS}=-10V$
$R_{DS(on)}$	Static Drain-Source	--	0.08	0.25	Ω	$V_{GS}=-10V, I_D=-1.0A$
	On-State Resistance ②	--	0.11	0.35		$V_{GS}=-4.5V, I_D=-0.5A$
g_{fs}	Forward Transconductance ②	--	5.0	--	S	$V_{DS}=-15V, I_D=-3.0A$
$t_{d(on)}$	Turn-On Delay Time	--	17	40	ns	$V_{DD}=-20V, I_D=-1.0A,$ $R_0=6.0\Omega,$ ②③
t_r	Rise Time	--	17	40		
$t_{d(off)}$	Turn-Off Delay Time	--	33	90		
t_f	Fall Time	--	19	50		
Q_g	Total Gate Charge	--	17	25	nC	$V_{DS}=-10V, V_{GS}=-10V,$ $I_D=-2.3A$ ②③
Q_{gs}	Gate-Source Charge	--	3.3	--		
Q_{gd}	Gate-Drain(" Miller ") Charge	--	3.6	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current (Body Diode)	--	--	-1.25	A	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier 
V_{SD}	Diode Forward Voltage ②	--	--	-1.6	V	$T_A=25^\circ\text{C}, I_S=-1.25A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time ②	--	100	--	ns	$T_A=25^\circ\text{C}, I_F=-1.25A, di_F/dt=100A/\mu s$

Notes ;

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ② Pulse Test : Pulse Width = $250\mu s$, Duty Cycle $\leq 2\%$
- ③ Essentially Independent of Operating Temperature

(N-Channel)

Fig 1. Output Characteristics

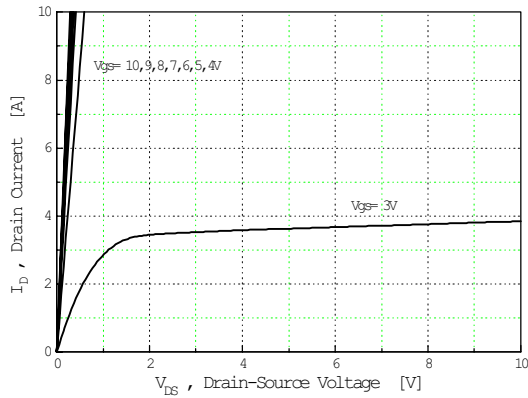


Fig 2. Transfer Characteristics

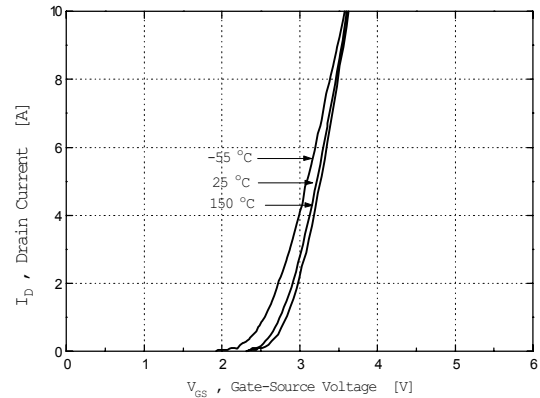


Fig 3. On-Resistance vs. Drain Current

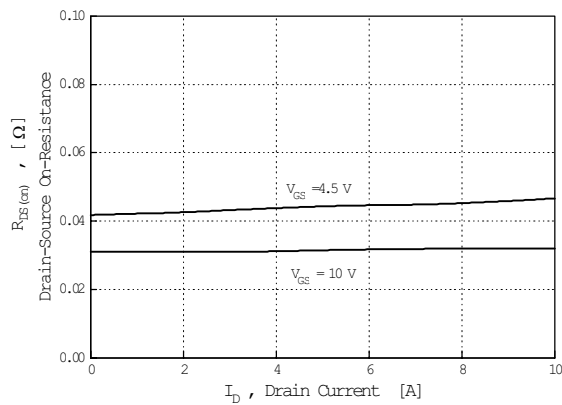


Fig 4. Source-Drain Forward Voltage

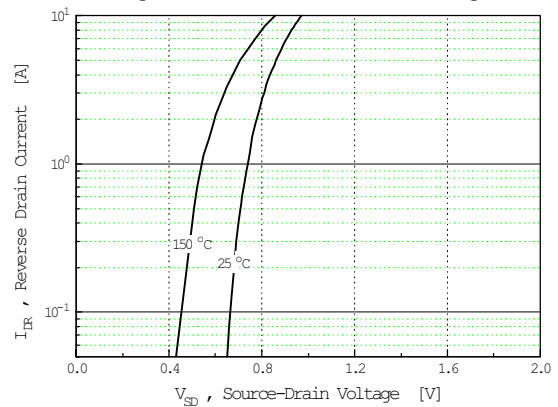


Fig 5. Capacitance vs. Drain-Source Voltage

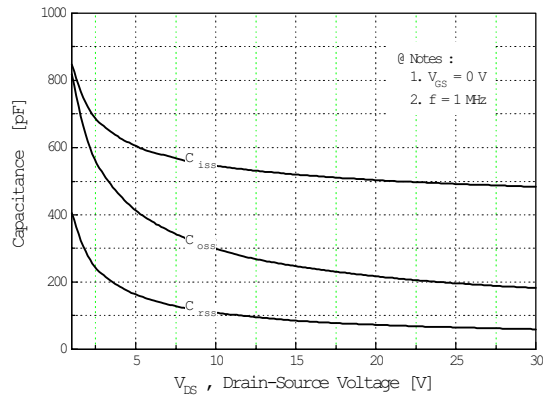
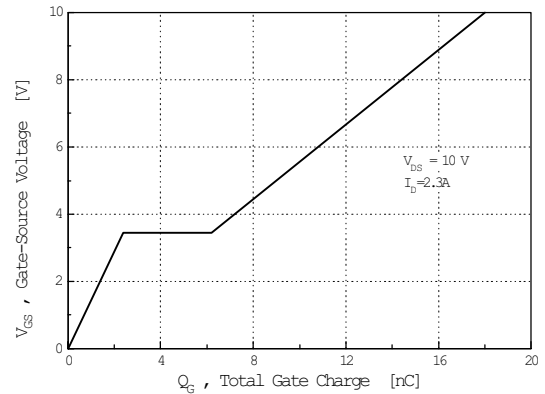


Fig 6. Gate Charge vs. Gate-Source Voltage



(N-Channel)

Fig 7. Breakdown Voltage vs. Temperature

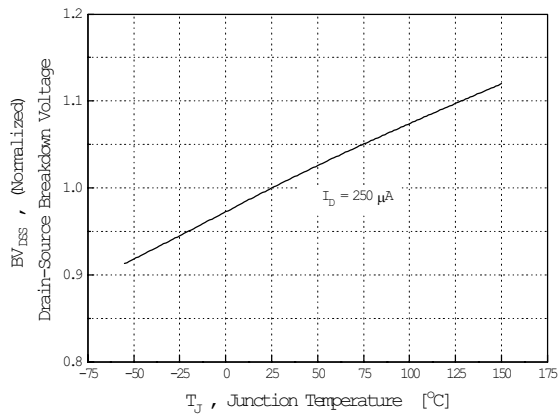


Fig 8. On-Resistance vs. Temperature

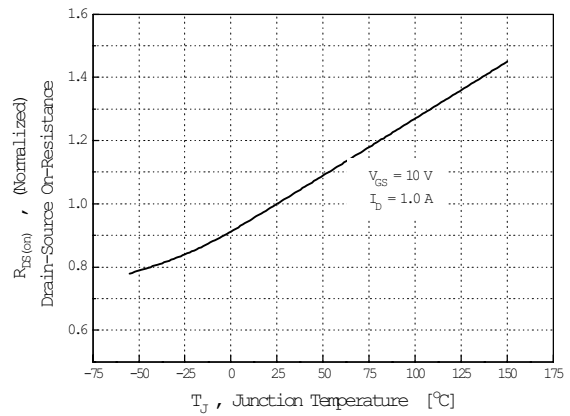
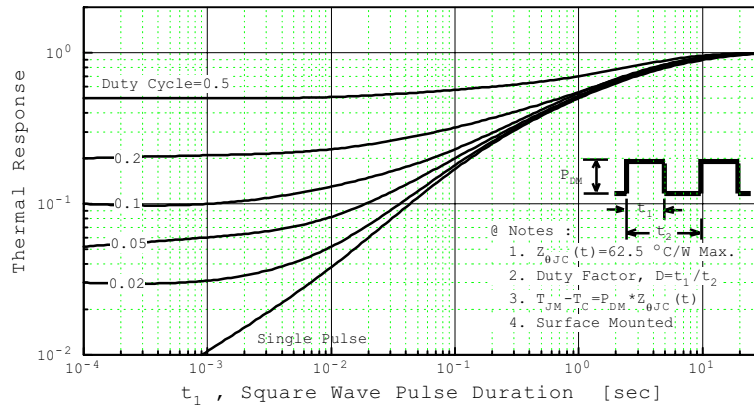


Fig 9. Normalized Effective Transient Thermal Impedance, Junction-to-Ambient



(P-Channel)

Fig 1. Output Characteristics

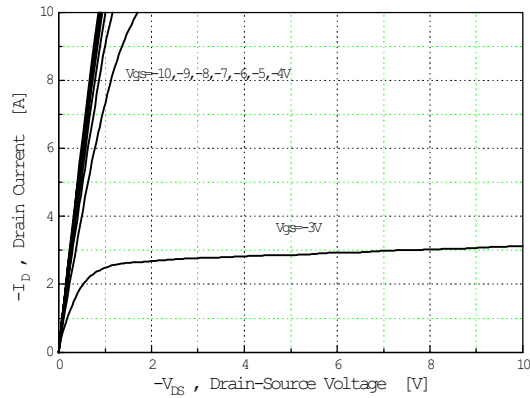


Fig 2. Transfer Characteristics

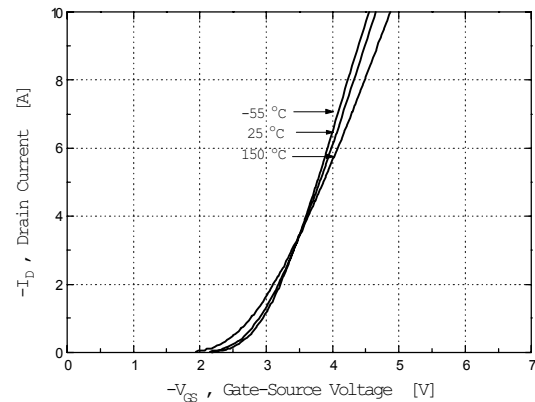


Fig 3. On-Resistance vs. Drain Current

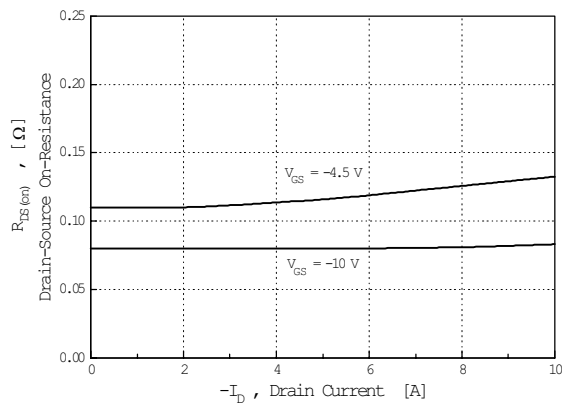


Fig 4. Source-Drain Forward Voltage

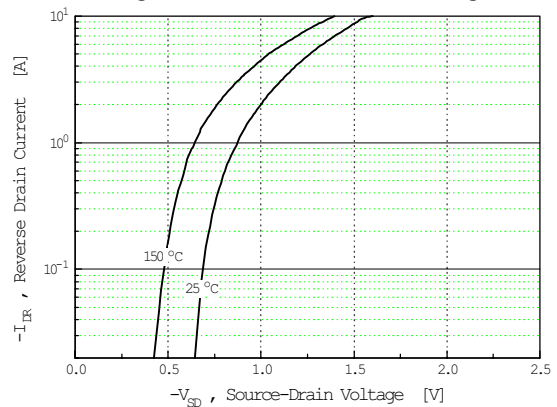


Fig 5. Capacitance vs. Drain-Source Voltage

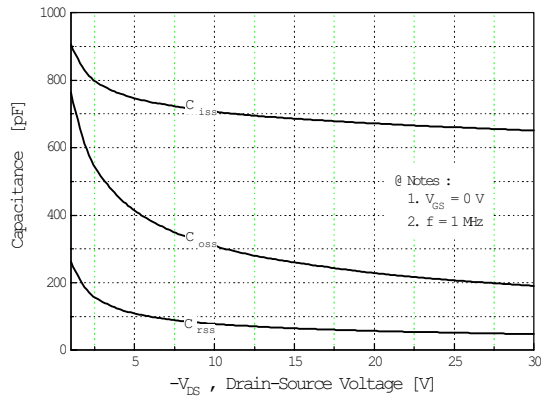
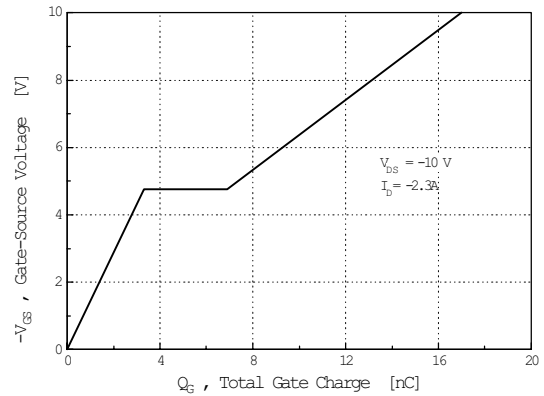


Fig 6. Gate Charge vs. Gate-Source Voltage



(P-Channel)

Fig 7. Breakdown Voltage vs. Temperature

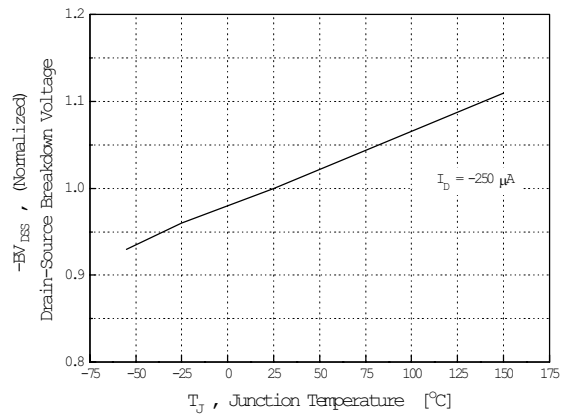


Fig 8. On-Resistance vs. Temperature

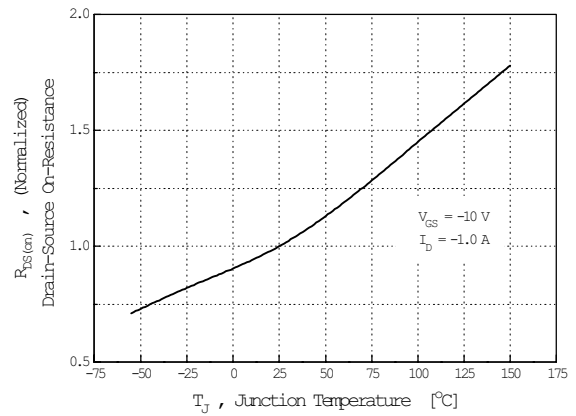


Fig 9. Normalized Effective Transient Thermal Impedance, Junction-to-Ambient

